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Lu, M. ; University of Edinburgh, Department of Electrical Engineering, Mayfield Road, Edinburgh, EH9 3JL, UK. Tel. 31 650 5661 Fax. 31 662 4358 ; Wang, G. ; Renshaw, D. ; Denyer, P.B.

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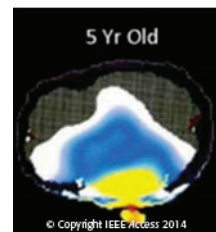
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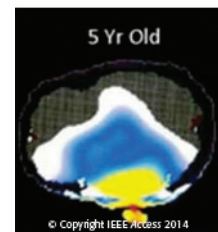
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